



PRODUCT AND PROCESS CHANGE NOTIFICATION
Generic Copy

ISSUE DATE: 01-Aug-2014
NOTIFICATION: 16307
TITLE: HIP7NVM MPC55XX BURN-IN HOUR REDUCTION TO 5 HOURS
EFFECTIVE DATE: 28-Jan-2015

DEVICE(S)

MPN
MPC5517BMLQX1
MPC5517BMLQX2
MPC5517BMLQX3
MPC5517BMLQX4
MPC5517DMLUX1
MPC5517DMLUX2
MPC5517DMLUX3
MPC5517DMLUX4
MPC5517EMLUX1
MPC5517EMLUX2
MPC5517EMLUX3
MPC5517EMLUX4
MPC5517FMLUX1
MPC5517FMLUX2
MPC5517FMLUX3
MPC5517FMLUX4
MPC5517GAVMG80
MPC5517MLQX1
MPC5517MLQX2
MPC5517MLQX3
MPC5517MLQX4
MPC5517MLUX1
MPC5517MLUX2
MPC5517MLUX3
MPC5517MLUX4
MPC5517MMGX1
MPC5517MMGX2
MPC5517MMGX3
MPC5517MMGX4
MPC5533MVFX1
MPC5533MVFX2
MPC5533MVFXXX
MPC5533MVMX1
MPC5533MVMX2
MPC5533MVMXXX

MPC5533MVZX1
MPC5533MVZX2
MPC5534MVFX1
MPC5534MVFX2
MPC5534MVM80
MPC5534MVMX1
MPC5534MVMX2
MPC5534MVZX1
MPC5534MVZX2
MPC5534MZQ80
MPC5534MZQX1
MPC5534MZQX2
MPC5553AZPTAUX2
MPC5553AZPXX
MPC5553MVFX1
MPC5553MVFX2
MPC5553MVFX3
MPC5553MVMX1
MPC5553MVMX3
MPC5553MVR132
MPC5553MVRX1
MPC5553MVRX2
MPC5553MVRX3
MPC5553MVZ132
MPC5553MVZX1
MPC5553MVZX2
MPC5553MVZX3
MPC5553MZP132
MPC5553MZP80
MPC5553MZPTAUX1
MPC5553MZPXX
MPC5553MZQ132
MPC5553MZQTAUX1
MPC5553MZQTAUX2
MPC5553MZQTAUX3
MPC5553MZQX1
MPC5553MZQX2
MPC5553MZQX3
MPC5554AZP132
MPC5554MVR132
MPC5554MVR80
MPC5554MVRX1
MPC5554MVRX2
MPC5554MVRXXX
MPC5554MZP112
MPC5554MZP112R2

MPC5554MZP132
MPC5554MZP132R2
MPC5554MZP80
MPC5554MZP80R2
MPC5554MZPJ1
MPC5554MZPJ2
MPC5554MZPJ3
MPC5554MZPT1
MPC5554MZPT2
MPC5554MZPT3
MPC5554MZPX1
MPC5554MZPX2
MPC5554MZPX3
MPC5561MZQX1
MPC5561MZQX2
MPC5561MZQX3
MPC5565MVZX1
MPC5565MVZX2
MPC5565MVZX3
MPC5565MZQX1
MPC5565MZQX2
MPC5565MZQX3
MPC5566MVR132
MPC5566MVRX1
MPC5566MVRX2
MPC5566MVRX3
MPC5566MVRX4
MPC5566MZP132
MPC5566MZP144
MPC5566MZPX1
MPC5566MZPX2
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MPC5566MZPX4
MPC5567MVR132
MPC5567MVZAX1
MPC5567MVZX1
MPC5567MVZX2
MPC5567MVZX3
MPC5567MZPAX1
MPC5567MZPX1
MPC5567MZPX2
MPC5567MZPX3
MPC5567MZQAX1
MPC5567MZQX1
MPC5567MZQX2
MPC5567MZQX3

SC5554MVRX1
SC5554MVRX2
SC5554MVRX3
SC5554MZP112
SC5554MZP112R2
SC5554MZP132
SC5554MZPTAUX1
SC5554MZPTAUX2
SC5554MZPTAUX3
SC5554MZPX1
SC5554MZPX2
SC5554MZPX3
SC5566MZPX1
SC5566MZPX2
SC5567MVR132
SC5567MVZX1
SC5567MVZX2
SC5567MVZX3
SC5567MZPX1
SC5567MZPX2
SCW5566
SPC5514EAMLQ66
SPC5514EBMLQ66
SPC5514EBVLQ66
SPC5514GBMLQ66
SPC5515SBCLQ48
SPC5515SBMLQ66
SPC5515SBMLQ66R
SPC5515SBVLQ48
SPC5515SBVLQ48R
SPC5516EACMG48
SPC5516EAMLQ48
SPC5516EAVLQ66
SPC5516EAVLQ66R
SPC5516EAVMG80
SPC5516EBMLQ66
SPC5516EBVLQ66
SPC5516GBMLQ66
SPC5516SBCLQ48
SPC5517EAMLU66
SPC5517EAVLQ66
SPC5517EAVLU66
SPC5517EAVMG80
SPC5517EBCLQ66
SPC5517EBCLQ66R
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SPC5517EBMLQ66R
SPC5517EBVLQ66
SPC5517EBVLQ66R
SPC5517GAMLQ66
SPC5517GAMLQ66R
SPC5517GAVMG80
SPC5517SACLU48
SPC5517SACLU66
SPC5517SAMLU66
SPC5517SBMLQ66
SPC5533MVF80
SPC5533MVF80R
SPC5533MVM80
SPC5533MVM80R
SPC5533MVZ80
SPC5533MVZ80R
SPC5534MVF80
SPC5534MVF80R
SPC5534MVM80
SPC5534MVM80R
SPC5534MVZ66
SPC5534MVZ80
SPC5534MVZ80R
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SPC5553MZQ132R
SPC5553MZQ80
SPC5553MZQ80R
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SPC5561F1MVZ132
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SPC5561F1MZQX1
SPC5561F1MZQX2
SPC5561F1MZQX3
SPC5561F2MVZ132

SPC5561F2MVZ132R
SPC5561F2MZQ132
SPC5561F2MZQ132R
SPC5565MVZ132
SPC5565MVZ132R
SPC5565MZQ132
SPC5565MZQ132R
SPC5566MVR132
SPC5566MVR132R
SPC5566MVR144
SPC5566MZP112
SPC5566MZP112R
SPC5566MZP132
SPC5566MZP132R
SPC5566MZP144
SPC5566MZP144R
SPC5566MZP80
SPC5566MZP80R
SPC5567MVR132
SPC5567MVR80
SPC5567MVR80R
SPC5567MVZ132
SPC5567MZP132
SPC5567MZQ132
SPC5567MZQ80
SPC5567MZQ80R

AFFECTED CHANGE CATEGORIES

- TEST PROCESS

DESCRIPTION OF CHANGE

Freescale is announcing the 5 hour Burn-In Optimization which leads to the reduction in duration for the Final Test production flow for the MPC55xx product family. No test steps were removed. The only change is a decrease in burn-in time which has been compensated with stress optimization.

Change	Current Production Burn-In Program (14 hours)	Proposed Production Burn-In Program (5 hours)	Time saving (hours)
<i>NVM write/erase cycle</i>	1500 cycles	100 cycles	2.5
<i>NVM read stress method</i>	NVM HTOL flash reads	NVM bulk read stress	2.0
<i>Scan and BIST duration</i>	60 minutes per download	20 minutes per download	1.5
<i>Buffer time for burn-in to complete</i>	4 hours	1 hour	3.0

This evaluation has been successfully completed according to Freescale specifications.

REASON FOR CHANGE

To improve manufacturing flexibility and customer support.

ANTICIPATED IMPACT OF PRODUCT CHANGE(FORM, FIT, FUNCTION, OR RELIABILITY)

None

According to JEDEC Standard JESD46, lack of acknowledgement of this PCN within 30 days will be considered acceptance of change. To request further data or inquire about the notification, please enter a [Service Request](#).

For sample inquiries - please go to www.freescale.com

QUAL DATA AVAILABILITY DATE: 16-Jun-2014

QUALIFICATION STATUS: COMPLETED

QUALIFICATION PLAN:

Refer to attached qualification report

RELIABILITY DATA SUMMARY:

Refer to attached qualification report

ELECTRICAL CHARACTERISTIC SUMMARY:

No significant difference between electrical characteristics.

CHANGED PART IDENTIFICATION:

There is no change to the orderable part number or marking.

ATTACHMENT(S):

External attachment(s) FOR this notification can be viewed AT:
[16307_MPC55xx_Burn-In_Reduction_1.pdf](#)
